

EXPANDED INDEXING & CITATION ANALYSIS COVERAGE OF IEEE CONTENT

As part of an ongoing effort to ensure broad access to its published content and to increase value to authors, IEEE has been working to expand coverage in indexing and citation analysis products - especially for conference publications. An interdepartmental staff team was recently formed specifically to address requests by the IEEE community to have content included in various abstracting and indexing (A&I) publications.

All IEEE content has been included in INSPEC for many years. INSPEC is currently the indexing layer used for IEEE Xplore.

With input from volunteers, the team is working to identify key A&I publishers and to establish more formal relationships with them. For example, starting with 2005 proceedings, Elsevier will be receiving all conference titles for inclusion in its many databases, including Engineering Index (Ei) and Ei Compendex. Negotiations are currently underway with other index providers such as MEDLINE.

In terms of citation analysis, the team recently met with a representative from Thomson Scientific, formerly ISI, to discuss opportunities for including conference content in one or more of its publications. (Thomson Scientific products include the Journal Citation Reports, Science Citation Index and Web of Science.) As a result, IEEE is now partnering with this publisher to determine how to best track and report citations for conference material, an issue of importance to virtually all conference publishers.

An update on this program will be circulated after the June 2006 IEEE Meeting Series.

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